


<b>Search Notes</b>  	<b>Application/Control No.</b>  10596782	<b>Applicant(s)/Patent Under Reexamination</b>  SCHLIWA-BERTLING ET AL.
	<b>Examiner</b>  WEI ZHAO	<b>Art Unit</b>  2475

SEARCHED			
Class	Subclass	Date	Examiner
370	229, 412, 235	6/15, 12/8	WZ
714	748	6/15	WZ

SEARCH NOTES		
Search Notes	Date	Examiner
Searched using US-PGPUB, USPAT, DERWENT, IBM_TDB in EAST	6/15	WZ
Did double patenting search and inventorship search for ODP in Palm Resource Center	6/15	WZ

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
370	412	6/15	WZ

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